DW OR N PACKAGE (TOP VIEW)

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- 8-Bit Resolution A/D Converter
- Microprocessor Peripheral or Stand-Alone Operation
- On-Chip 12-Channel Analog Multiplexer
- Built-In Self-Test Mode
- Software-Controllable Sample and Hold
- Total Unadjusted Error . . . ±0.5 LSB Max
- TLC541 Is Direct Replacement for Motorola MC145040 and National Semiconductor ADC0811. TLC540 Is Capable of Higher Speed
- Pinout and Control Signals Compatible With TLC1540 Family of 10-Bit A/D Converters
- CMOS Technology

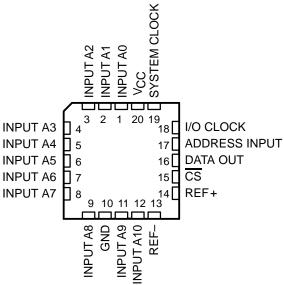
PARAMETER	TLC540	TLC541
Channel Acquisition Sample Time	2 μs	3.6 μs
Conversion Time (Max)	9 μs	17 μs
Samples per Second (Max)	75 x 10 ³	40 x 10 ³
Power Dissipation (Max)	12.5 mW	12.5 mW

description

The TLC540 and TLC541 are CMOS A/D converters built around an 8-bit switched-capacitor successive-approximation A/D converters. They are designed for serial interface to a microprocessor or peripheral via a 3-state output with up to four control inputs, including independent SYSTEM CLOCK, I/O CLOCK, chip select (CS), and ADDRESS INPUT. A 4-MHz system clock for the TLC540 and a 2.1-MHz system clock for the TLC541 with a design that

INPUT A0 20 VCC INPUT A1 1 2 19 SYSTEM CLOCK INPUT A2 [] 3 18 [] I/O CLOCK INPUT A3 **1** 4 17 ADDRESS INPUT INPUT A4 I 5 16 DATA OUT INPUT A5 **1** 6 15 T CS 14 NEF+ INPUT A6 [13**∏** REF-INPUT A7 **1**8 INPUT A8 **∏** 9 12 | INPUT A10 GND [11 NPUT A9

FN PACKAGE (TOP VIEW)



includes simultaneous read/write operation allow high-speed data transfers and sample rates of up to 75,180samples per second for the TLC540 and 40,000 samples per second for the TLC541. In addition to the high-speed converter and versatile control logic, there is an on-chip 12-channel analog multiplexer that can be used to sample any one of 11 inputs or an internal self-test voltage, and a sample-and-hold that can operate automatically or under microprocessor control.

AVAILABLE OPTIONS

	PACKAGE								
TA	SO PLASTIC DIP	PLASTIC DIP	CHIP CARRIER						
	(DW)	(N)	(FN)						
-40°C to 85°C	—	TLC540IN	TLC540IFN						
	TLC541IDW	TLC541IN	TLC541IFN						
-55°C to 125°C	_	TLC541MN	_						



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

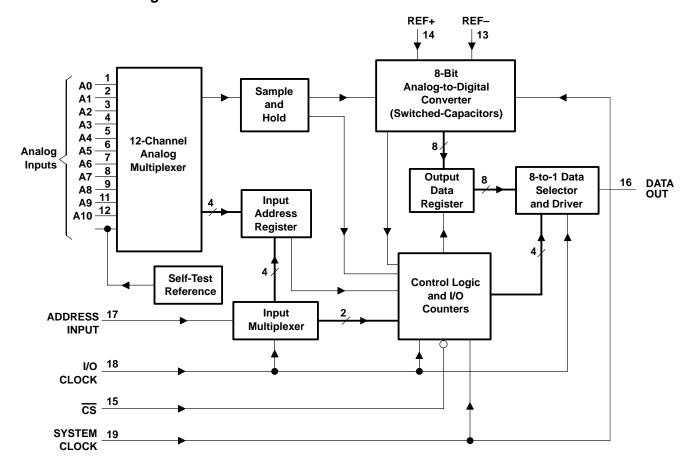


description (continued)

The converters incorporated in the TLC540 and TLC541 feature differential high-impedance reference inputs that facilitate ratiometric conversion, scaling, and analog circuitry isolation from logic and supply noises. A switched-capacitor design allows low-error (± 0.5 LSB) conversion in 9 μ s for the TLC540 and 17 μ s for the TLC541 over the full operating temperature range.

The TLC540I and TLC541I are characterized for operation from -40° C to 85° C. The TLC541M is characterized for operation from -55° C to 125° C.

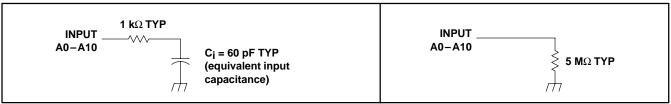
functional block diagram



typical equivalent inputs

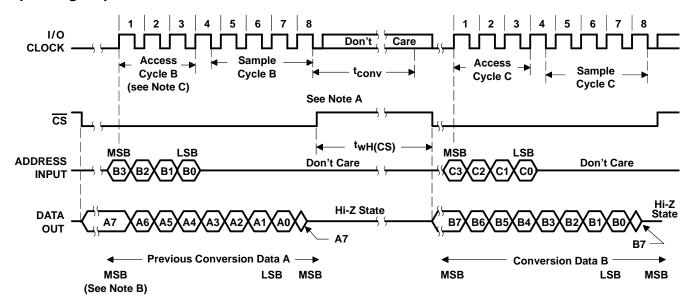
INPUT CIRCUIT IMPEDANCE DURING SAMPLING MODE

INPUT CIRCUIT IMPEDANCE DURING HOLD MODE





operating sequence



- NOTES: A. The conversion cycle, which requires 36 system clock periods, is initiated on the 8th falling edge of I/O CLOCK after CS goes low for the channel whose address exists in memory at that time. If CS is kept low during conversion, I/O CLOCK must remain low for at least 36 system clock cycles to allow conversion to be completed.
 - B. The most significant bit (MSB) will automatically be placed on the DATA OUT bus after $\overline{\text{CS}}$ is brought low. The remaining seven bits (A6–A0) will be clocked out on the first seven I/O CLOCK falling edges.
 - C. To minimize errors caused by noise at $\overline{\text{CS}}$, the internal circuitry waits for three system clock cycles (or less) after a chip select falling edge is detected before responding to control input signals. Therefore, no attempt should be made to clock-in address data until the minimum chip-select setup time has elapsed.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC} (see Note 1)	6.5 V
Input voltage range, V _I (any input)	-0.3 V to V _{CC} +0.3 V
Output voltage range, V _O	-0.3 V to V _{CC} +0.3 V
Peak input current range (any input)	±10 mA
Peak total input current (all inputs)	±30 mA
Operating free-air temperature range, T _A : TLC540I, TLC541I	–40°C to 85°C
Storage temperature range, T _{stq}	–65°C to 150°C
Case temperature for 10 seconds: FN package	
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds: DW or N package $$.	260°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values are with respect to digital ground with REF- and GND wired together (unless otherwise noted).



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recommended operating conditions

				TLC540			TLC541		UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Supply voltage, V _{CC}			4.75	5	5.5	4.75	5	5.5	V
Positive reference voltage,	V _{ref+} (see	Note 2)	2.5	Vcc	V _{CC} +0.1	2.5	Vcc	V _{CC} +0.1	V
Negative reference voltage	Negative reference voltage, V _{ref} (see Note 2)					- 0.1	0	2.5	V
Differential reference voltage	Differential reference voltage, V _{ref+} – V _{ref-} (see Note 2)					1	VCC	V _{CC} +0.2	V
Analog input voltage (see N	lote 2)		0		VCC	0		Vcc	V
High-level control input volt	age, V _{IH}		2			2			V
Low-level control input volta	age, V _{IL}				0.8			0.8	V
Setup time, address bits at t _{su} (A)	data input	before I/O CLOCK↑,	200			400			ns
Hold time, address bits after	Hold time, address bits after I/O CLOCK↑, th(A)					0			ns
Setup time, CS low before (see Note 3)	3			3			System clock cycles		
CS high during conversion,	^t wH(CS)		36			36			System clock cycles
I/O CLOCK frequency, fcloo	ck(I/O)		0		2.048	0		1.1	MHz
Pulse duration, SYSTEM C	LOCK free	quency, f _{clock} (SYS)	fclock(I/O)		4	fclock(I/O)		2.1	MHz
Pulse duration, SYSTEM C	LOCK higl	^{h, t} wH(SYS)	110			210			MHz
Pulse duration, SYSTEM C	LOCK low	, t _w L(SYS)	100			190			MHz
Pulse duration, I/O clock hi	gh, t _{wH(I/C}	D)	200			404			ns
Pulse duration, I/O clock lo	w, t _{wL(I/O)}		200			404			ns
	System	f _{clock} (SYS) ≤ 1048 kHz			30			30	
Clock transition time	System	f _{clock(SYS)} > 1048 kHz			20			20	20
(see Note 4)	I/O	f _{clock(I/O)} ≤ 525 kHz	1		100			100	ns
	1/0	f _{clock(I/O)} > 525 kHz			40			40	
Operating free-air temperat	ure, TA	TLC540I, TLC541I	-40		85	-40		85	°C

- NOTES: 2. Analog input voltages greater than that applied to REF + convert as all 1s (11111111), while input voltages less than that applied to REF- convert as all 0s (00000000). For proper operation, REF+ voltage must be at least 1 V higher than REF- voltage. Also, the total unadjusted error may increase as this differential reference voltage falls below 4.75 V.
 - 3. To minimize errors caused by noise at \overline{CS} , the internal circuitry waits for three SYSTEM CLOCK cycles (or less) after a chip select falling edge is detected before responding to control input signals. Therefore, no attempt should be made to clock in an address until the minimum chip select setup time has elapsed.
 - 4. This is the time required for the clock input signal to fall from V_{IH} min to V_{IL} max or to rise from V_{IL} max to V_{IH} min. In the vicinity of normal room temperature, the devices function with input clock transition time as slow as 2 μs for remote data acquisition applications where the sensor and the A/D converter are placed several feet away from the controlling microprocessor.



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electrical characteristics over recommended operating temperature range, $V_{CC} = V_{ref+} = 4.75 \text{ V}$ to 5.5 V, $f_{clock(I/O)} = 2.048 \text{ MHz}$ for TLC540 or $f_{clock(I/O)} = 1.1 \text{ MHz}$ for TLC541 (unless otherwise noted)

	PAF	RAMETER	TEST CO	NDITIONS	MIN	TYP†	MAX	UNIT
Vон	High-level output vo	ltage, DATA OUT	$V_{CC} = 4.75 \text{ V},$	ΙΟΗ = 360 μΑ	2.4			V
VOL	Low-level output vol	tage	$V_{CC} = 4.75 \text{ V},$	I_{OL} = 1.6 mA			0.4	V
lo-	Off state (high impo	dance state) output current	$V_O = V_{CC}$	CS at V _{CC}			10	μΑ
loz	On-state (nigh-impe	dance state) output current	$V_{O} = 0$,	CS at V _{CC}			-10	
۱н	High-level input curr	rent	VI =VCC			0.005	2.5	μΑ
I _I L	Low-level input curre	ent	V _I = 0			-0.005	-2.5	μΑ
Icc	Operating supply cu	irrent	CS at 0 V			1.2	2.5	mA
	Calcatad abancalla		Selected channels Unselected characteristics			0.4	1	4
	Selected channel le	akage current	Selected chann Unselected cha	′	-0.4	-1	μΑ	
ICC + Iref	Supply and reference	ce current	$V_{ref+} = V_{CC}$	CS at 0 V		1.3	3	mA
C.	Input capacitance	Analog inputs				7	55	pF
Ci	при сараспансе	Control inputs				5	15	PΓ

[†] All typical values are at $T_A = 25$ °C.

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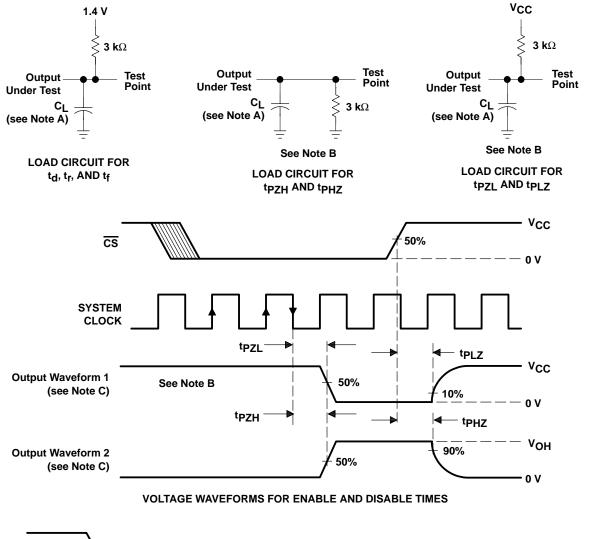
operating characteristics over recommended operating free-air temperature range, $V_{CC} = V_{ref+} - 4.75$ V to 5.5 V, $f_{clock(I/O)} = 2.048$ MHz for TLC540 or 1.1 MHz for TLC541, $f_{clock(SYS)} = 4$ MHz for TLC540 or 2.1 MHz for TLC541

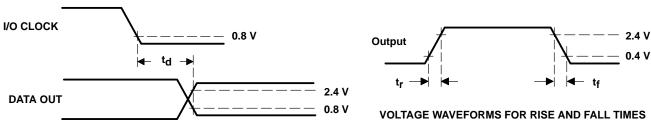
	PARAMETER	TEST CONDITIONS	TLC	540	TLC	541	UNIT
	PARAMETER	TEST CONDITIONS	MIN	MAX	MIN	MAX	UNIT
EL	Linearity error	See Note 5		±0.5		±0.5	LSB
EZS	Zero-scale error	See Notes 2 and 6		±0.5		±0.5	LSB
EFS	Full-scale error	See Notes 2 and 6		±0.5		±0.5	LSB
	Total unadjusted error	See Note 7		±0.5		±0.5	LSB
	Self-test output code	Input A11 address = 1011, (see Note 8)	01111101 (125)	10000011 (131)	01111101 (125)	10000011 (131)	
t _{conv}	Conversion time	See operating sequence		9		17	μs
	Total access and conversion time	See operating sequence		13.3		25	μs
ta	Channel acquisition time (sample cycle)	See operating sequence		4		4	I/O clock cylces
t _V	Time output data remains valid after I/O CLOCK↓		10		10		ns
td	Delay time, I/O CLOCK↓ to data output valid			300		400	ns
t _{en}	Output enable time	See Parameter		150		150	ns
t _{dis}	Output disable time	Measurement Information		150		150	ns
t _{r(bus)}	Data bus rise time			300		300	ns
t _f (bus)	Data bus fall time]		300		300	ns

- NOTES: 2. Analog input voltages greater than that applied to REF+ convert to all 1s (11111111) while input voltages less than that applied to REF- convert to all 0s (00000000). For proper operation, REF+ voltage must be at least 1 V higher than REF- voltage. Also, the total unadjusted error may increase as this differential reference voltage falls below 4.75 V.
 - 5. Linearity error is the maximum deviation from the best straight line through the A/D transfer characteristics.
 - 6. Zero-scale error is the difference between 00000000 and the converted output for zero input voltage; full-scale error is the difference between 11111111 and the converted output for full-scale input voltage.
 - 7. Total unadjusted error is the sum of linearity, zero-scale, and full-scale errors.
 - 8. Both the input address and the output codes are expressed in positive logic.



PARAMETER MEASUREMENT INFORMATION





VOLTAGE WAVEFORMS FOR DELAY TIME

NOTES: A. $C_L = 50 \text{ pF}$ for TLC540 and 100 pF for TLC541.

- B. $t_{en} = t_{PZH}$ or t_{PZL} , $t_{dis} = t_{PHZ}$ or t_{PLZ} .
- C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.



APPLICATION INFORMATION

simplified analog input analysis

Using the equivalent circuit in Figure 1, the time required to charge the analog input capacitance from 0 to V_S within 1/2 LSB can be derived as follows:

The capacitance charging voltage is given by

$$V_{C} = V_{S} \left(1 - e^{-t_{C}/R_{t}C_{i}} \right)$$
 (1)

where

$$R_t = R_s + r_i$$

The final voltage to 1/2 LSB is given by

$$V_C (1/2 LSB) = V_S - (V_S/512)$$
 (2)

Equating equation 1 to equation 2 and solving for time t_c gives

$$V_{S} - \left(V_{S}/512\right) = V_{S}\left(1 - e^{-t_{C}/R_{t}C_{i}}\right)$$
(3)

and

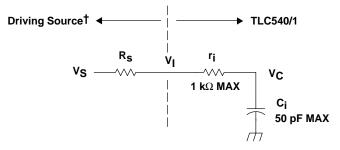
$$t_{c} (1/2 LSB) = R_{t} \times C_{j} \times \ln(512)$$

$$\tag{4}$$

Therefore, with the values given the time for the analog input signal to settle is

$$t_{\rm C} (1/2 \text{ LSB}) = (R_{\rm S} + 1 \text{ k}\Omega) \times 60 \text{ pF} \times \ln(512)$$
 (5)

This time must be less than the converter sample time shown in the timing diagrams.



V_I = Input Voltage at INPUT A0-A10

VS = External Driving Source Voltage

R_S = Source Resistance

ri = Input Resistance

C_i = Equivalent Input Capacitance

† Driving source requirements:

- Noise and distortion for the source must be equivalent to the resolution of the converter.
- R_S must be real at the input frequency.

Figure 1. Equivalent Input Circuit Including the Driving Source



PRINCIPLES OF OPERATION

The TLC540 and TLC541 are each complete data acquisition systems on a single chip. They include such functions as analog multiplexer, sample and hold, 8-bit A/D converter, data and control registers, and control logic. For flexibility and access speed, there are four control inputs [two clocks, chip select (\overline{CS}) , and address]. These control inputs and a TTL-compatible 3-state output are intended for serial communications with a microprocessor or microcomputer. With judicious interface timing, with TLC540 a conversion can be completed in 9 μ s, while complete input-conversion-output cycles can be repeated every 13 μ s. With TLC541 a conversion can be completed in 17 μ s, while complete input-conversion-output cycles are repeated every 25 μ s. Furthermore, this fast conversion can be executed on any of 11 inputs or its built-in self-test and in any order desired by the controlling processor.

The system and I/O clocks are normally used independently and do not require any special speed or phase relationships between them. This independence simplifies the hardware and software control tasks for the device. Once a clock signal within the specification range is applied to SYSTEM CLOCK, the control hardware and software need only be concerned with addressing the desired analog channel, reading the previous conversion result, and starting the conversion by using I/O CLOCK. SYSTEM CLOCK will drive the conversion crunching circuitry so that the control hardware and software need not be concerned with this task.

When \overline{CS} is high, DATA OUT is in a 3-state condition and ADDRESS INPUT and I/O CLOCK are disabled. This feature allows each of these terminals, with the exception of \overline{CS} , to share a control logic point with their counterpart terminals on additional A/D devices when additional TLC540/541 devices are used. In this way, the above feature serves to minimize the required control logic terminals when using multiple A/D devices.

The control sequence has been designed to minimize the time and effort required to initiate conversion and obtain the conversion result. A normal control sequence is:

- 1. \overline{CS} is brought low. To minimize errors caused by noise at \overline{CS} , the internal circuitry waits for two rising edges and then a falling edge of SYSTEM CLOCK after a low \overline{CS} transition, before the low transition is recognized. This technique is used to protect the device against noise when the device is used in a noisy environment. The MSB of the previous conversion result automatically appears on DATA OUT.
- 2. A new positive-logic multiplexer address is shifted in on the first four rising edges of I/O CLOCK. The MSB of the address is shifted in first. The negative edges of these four I/O clock pulses shift out the second, third, fourth, and fifth most significant bits of the previous conversion result. The on-chip sample and hold begins sampling the newly addressed analog input after the fourth falling edge. The sampling operation basically involves the charging of internal capacitors to the level of the analog input voltage.
- 3. Three clock cycles are then applied to I/O CLOCK and the sixth, seventh, and eighth conversion bits are shifted out on the negative edges of these clock cycles.
- 4. The final eighth clock cycle is applied to I/O CLOCK. The falling edge of this clock cycle completes the analog sampling process and initiates the hold function. Conversion is then performed during the next 36 system clock cycles. After this final I/O clock cycle, CS must go high or the I/O CLOCK must remain low for at least 36 system clock cycles to allow for the conversion function.

 $\overline{\text{CS}}$ can be kept low during periods of multiple conversion. When keeping $\overline{\text{CS}}$ low during periods of multiple conversion, special care must be exercised to prevent noise glitches on I/O CLOCK. If glitches occur on I/O CLOCK, the I/O sequence between the microprocessor/controller and the device loses synchronization. Also, if $\overline{\text{CS}}$ is taken high, it must remain high until the end of the conversion. Otherwise, a valid falling edge of $\overline{\text{CS}}$ causes a reset condition, which aborts the conversion in progress.

A new conversion can be started and the ongoing conversion simultaneously aborted by performing steps 1 through 4 before the 36 system clock cycles occur. Such action yields the conversion result of the previous conversion and not the ongoing conversion.



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PRINCIPLES OF OPERATION

It is possible to connect SYSTEM CLOCK and I/O clock together in special situations in which controlling circuitry points must be minimized. In this case, the following special points must be considered in addition to the requirements of the normal control sequence previously described.

- 1. The first two clocks are required for this device to recognize \overline{CS} is at a valid low level when the common clock signal is used as an I/O CLOCK. When \overline{CS} is recognized by the device to be at a high level, the common clock signal is used for the conversion clock also.
- 2. A low $\overline{\text{CS}}$ must be recognized before the I/O CLOCK can shift in an analog channel address. The device recognizes a $\overline{\text{CS}}$ transition when the SYSTEM CLOCK terminal receives two positive edges and then a negative edge. For this reason, after a $\overline{\text{CS}}$ negative edge, the first two clock cycles do not shift in the address. Also, upon shifting in the address, $\overline{\text{CS}}$ must be raised after the eighth valid (10 total) I/O CLOCK. Otherwise, additional common clock cycles are recognized as I/O CLOCKS and will shift in an erroneous address.

For certain applications, such as strobing applications, it is necessary to start conversion at a specific point in time. This device accommodates these applications. Although the on-chip sample and hold begins sampling upon the negative edge of the fourth valid I/O clock cycle, the hold function is not initiated until the negative edge of the eighth valid I/O clock cycle. Thus, the control circuitry can leave the I/O clock signal in its high state during the eighth valid I/O clock cycle until the moment at which the analog signal must be converted. The TLC540/TLC541 continues sampling the analog input until the eighth falling edge of the I/O clock. The control circuitry or software then immediately lowers the I/O clock signal and holds the analog signal at the desired point in time and start conversion.

Detailed information on interfacing to most popular microprocessors is readily available from the factory.







10-Jun-2014

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
TLC540IDW	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM		TLC540I	Samples
TLC540IDWR	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM		TLC540I	Samples
TLC540IFN	ACTIVE	PLCC	FN	20	46	Green (RoHS & no Sb/Br)	CU SN	Level-1-260C-UNLIM		TLC540I	Samples
TLC540IFNG3	ACTIVE	PLCC	FN	20	46	Green (RoHS & no Sb/Br)	CU SN	Level-1-260C-UNLIM		TLC540I	Samples
TLC540IFNR	ACTIVE	PLCC	FN	20	1000	Green (RoHS & no Sb/Br)	CU SN	Level-1-260C-UNLIM		TLC540I	Samples
TLC540IFNRG3	ACTIVE	PLCC	FN	20	1000	Green (RoHS & no Sb/Br)	CU SN	Level-1-260C-UNLIM		TLC540I	Samples
TLC540IN	ACTIVE	PDIP	N	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type		TLC540IN	Samples
TLC540INE4	ACTIVE	PDIP	N	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type		TLC540IN	Samples
TLC541IDW	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM		TLC541I	Samples
TLC541IDWG4	ACTIVE	SOIC	DW	20	25	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM		TLC541I	Samples
TLC541IDWR	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM		TLC541I	Samples
TLC541IDWRG4	ACTIVE	SOIC	DW	20	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM		TLC541I	Samples
TLC541IFN	ACTIVE	PLCC	FN	20	46	Green (RoHS & no Sb/Br)	CU SN	Level-1-260C-UNLIM		TLC541I	Samples
TLC541IFNG3	ACTIVE	PLCC	FN	20	46	Green (RoHS & no Sb/Br)	CU SN	Level-1-260C-UNLIM		TLC541I	Samples
TLC541IFNR	ACTIVE	PLCC	FN	20	1000	Green (RoHS & no Sb/Br)	CU SN	Level-1-260C-UNLIM		TLC541I	Samples
TLC541IN	ACTIVE	PDIP	N	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type		TLC541IN	Samples
TLC541INE4	ACTIVE	PDIP	N	20	20	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type		TLC541IN	Samples



PACKAGE OPTION ADDENDUM

10-Jun-2014

Orderable Device	Status	Package Type	Package	Pins Package	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing	Qty	(2)	(6)	(3)		(4/5)	
TLC541MN	OBSOLETE	PDIP	N	20	TBD	Call TI	Call TI	-55 to 125		

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free** (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

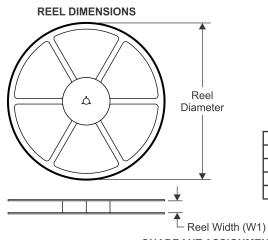
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PACKAGE MATERIALS INFORMATION

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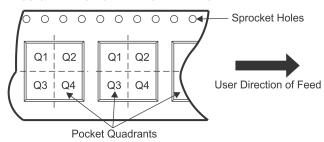
TAPE AND REEL INFORMATION





A0	
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

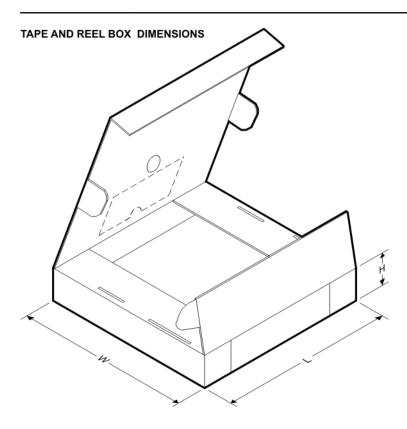


*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TLC540IDWR	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
TLC541IDWR	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1

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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TLC540IDWR	SOIC	DW	20	2000	367.0	367.0	45.0
TLC541IDWR	SOIC	DW	20	2000	367.0	367.0	45.0

DW (R-PDSO-G20)

PLASTIC SMALL OUTLINE



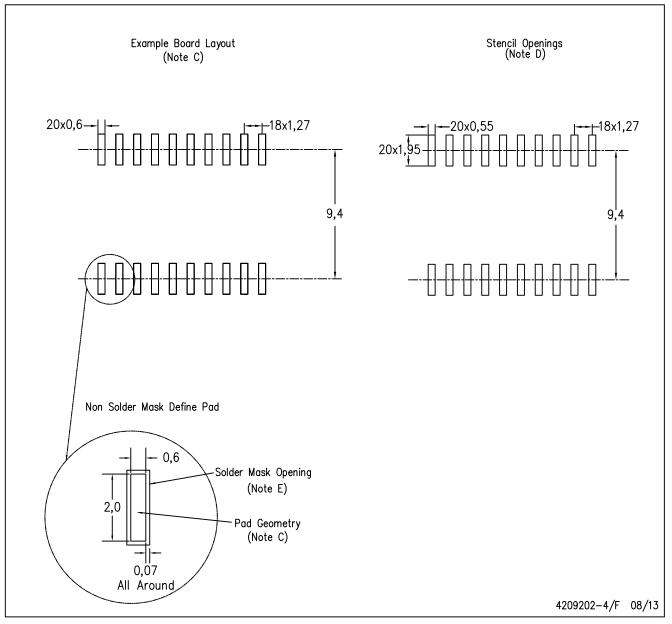
NOTES: A. All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013 variation AC.



DW (R-PDSO-G20)

PLASTIC SMALL OUTLINE



NOTES:

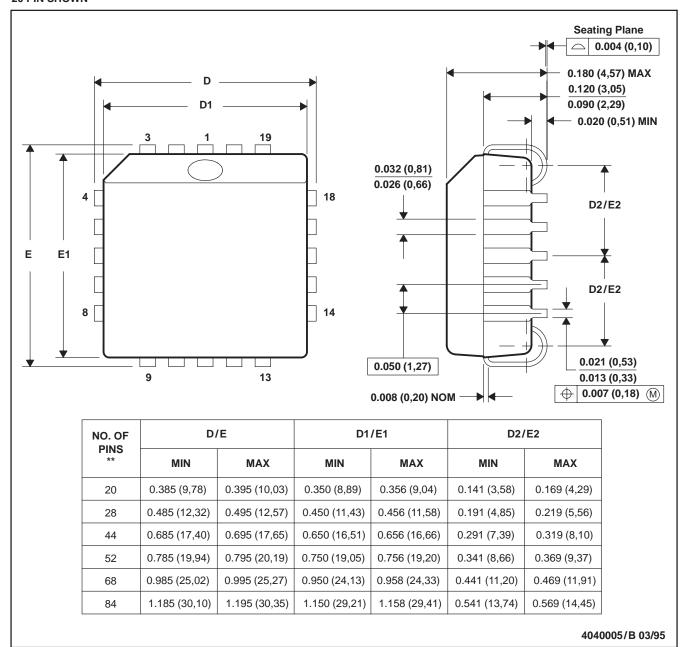
- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Refer to IPC7351 for alternate board design.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



FN (S-PQCC-J**)

20 PIN SHOWN

PLASTIC J-LEADED CHIP CARRIER



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

C. Falls within JEDEC MS-018

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